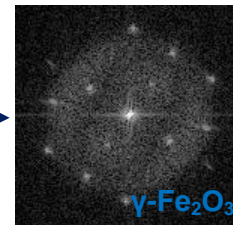
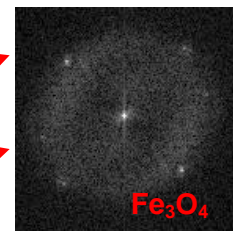
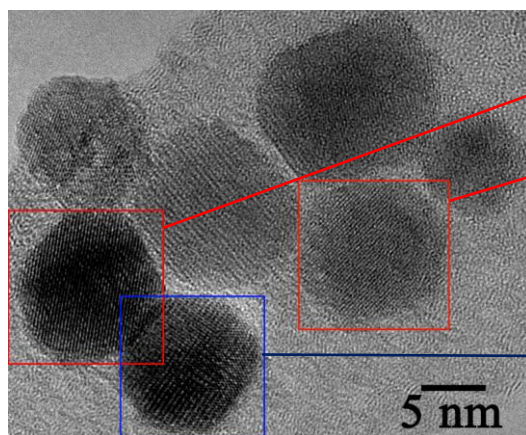


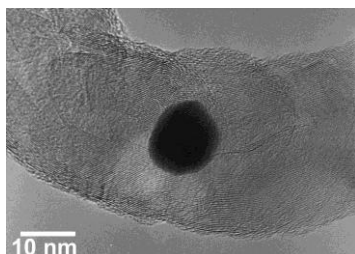


High Resolution Transmission Electron Microscope JEOL JEM-2011-HR

- Transmission Electron Microscopy (BF, DF, HRTEM)
- Electron Diffraction (SAED, CBED, nanodiffraction)
- Energy-Dispersive X-ray Spectroscopy (EDXS),
- Oxford Instruments INCA Suite v.4.02, detection from Be on
- Thermionic emitter (LaB₆ crystal)
- Acceleration voltage: 200 kV
- Point-resolution: ≤ 0.23 nm (Cs= 1.0 mm)
- Lattice resolution in HRTEM: ≤ 0.14 nm



Magnetic nanoparticles indicating two different crystallographic phases



Carbon nanotube and a nickel nanoparticle that has been grown internally

Contact:

Dr. Andreas Delimitis
Chemical Process & Energy Resources Inst.
Centre for Research & Technology – Hellas)
P.O.Box 60361 Themi, Thessaloniki
Greece

Tel:+30-2310-498259
Fax:+30-2310-498131
andel@cperi.certh.gr
<http://www.certh.gr>